

PATENT NUMBER

U.S. UTILITY Patent Application

O.I.P.E. hp IK4 SCANNED Q.A.	PATENT DATE
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APPLICATION NO. 09/939636	CONT/PRIOR	CLASS 257	SUBCLASS 25	ART UNIT 2815	EXAMINER
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Kevin Devereaux

Method and apparatus for wafer level testing of semiconductor using sacrificial on die power and ground metalization

PTO-2040
12/99

ISSUING CLASSIFICATION										
ORIGINAL				CROSS REFERENCE(S)						
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
INTERNATIONAL CLASSIFICATION										

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<input type="checkbox"/> TERMINAL DISCLAIMER	DRAWINGS		CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims
<input type="checkbox"/> The term of this patent subsequent to _____ (date) has been disclaimed.	_____ (Assistant Examiner)		_____ (Date)	
	<input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S. Patent. No. _____ _____ _____ _____		NOTICE OF ALLOWANCE MAILED	
ISSUE FEE				
<input type="checkbox"/> The terminal _____ months of this patent have been disclaimed.	_____ (Primary Examiner)		Amount Due	Date Paid
	_____ (Legal Instruments Examiner)		ISSUE BATCH NUMBER	

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